Modeling and Design of Integrated CMOS Circuit

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Message from the Guest Editors

One of the main challenges for the electronic research field is to cope with the rapidly progressing technology which, today, reaches the nanometer scale and ultra-low voltages. The areas of interest of this Special Issue include the modeling and design of innovative chips and embedded systems. Emerging technologies have raised relevant topics related to performances, power, and reliability that to need to be investigated.

The topics of this Special Issue are dedicated but not limited to the following:

System-on-a-chip;

multiprocessor systems;

network-on-a-chip;

low-voltage and low-power systems;

Internet of Things sensor;

analog–digital convertor/digital–analog converter;

clock network;

emerging type of memories;

CMOS image sensors

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Special Issue

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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